

These miniature surface mount MOSFETs utilize a high cell density trench process to provide low $r_{DS(on)}$ and to ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

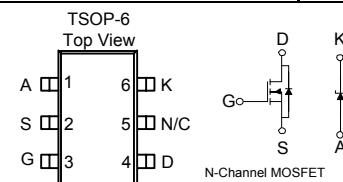
- Low $r_{DS(on)}$ provides higher efficiency and extends battery life
- Low thermal impedance copper leadframe TSOP-6 saves board space
- Fast switching speed
- High performance trench technology

MOSFET PRODUCT SUMMARY

V_{DS} (V)	r_{DS(on)} (OHM)	I_D (A)
20	0.047 @ V _{GS} = -4.5V	±4.1
	0.055 @ V _{GS} = -2.5V	±3.8

SCHOTTKY PRODUCT SUMMARY

V_{KA} (V)	V_f (V) Diode Forward Voltage	I_F (A)
20	0.48V @ 1.0A	1.0



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C UNLESS OTHERWISE NOTED)

Parameter	Symbol	Maximum	Units
Drain-Source Voltage (MOSFET)	V _{DS}	20	V
Reverse Voltage (Schottky)	V _{KA}	20	
Gate-Source Voltage (MOSFET)	V _{GS}	±8	
Continuous Drain Current (T _J =150°C) (MOSFET) ^a	I _D	±4.1	A
		±3.3	
Pulsed Drain Current (MOSFET) ^b	I _{DM}	±8	A
Continuous Source Current (MOSFET Diode Conduction) ^a	I _S	1.05	
Average Forward Current (Schottky)	I _F	0.5	
Pulsed Forward Current (Schottky)	I _{FM}	8	
Maximum Power Dissipation (MOSFET) ^a	P _D	1.15	W
		0.7	
Maximum Power Dissipation (Schottky) ^a		1.0	
		0.6	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typ	Max	
Maximum Junction-to-Ambient ^a	R _{thJA}	93	110	°C/W
		130	150	

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- Pulse width limited by maximum junction temperature

MOSFET SPECIFICATIONS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Conditions	Limits			Unit
			Min	Typ	Max	
Static						
Gate-Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.4			
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = +/-8 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$		1		μA
		$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$		10		
On-State Drain Current ^A	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	5			A
Drain-Source On-State Resistance ^A	$r_{DS(\text{on})}$	$V_{GS} = 4.5 \text{ V}, I_D = 4.1 \text{ A}$			0.047	Ω
		$V_{GS} = 2.5 \text{ V}, I_D = 3.8 \text{ A}$			0.055	
Forward Transconductance ^A	g_{fs}	$V_{DS} = 5 \text{ V}, I_D = 4.1 \text{ A}$		3		S
Diode Forward Voltage	V_{SD}	$I_S = 1.05 \text{ A}, V_{GS} = 0 \text{ V}$		0.80		V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 4.1 \text{ A}$		7.5		nC
Gate-Source Charge	Q_{gs}			0.6		
Gate-Drain Charge	Q_{gd}			1.0		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 5 \text{ V}, R_L = 5 \text{ OHM}, V_{GEN} = 4.5 \text{ V}, R_G = 6 \text{ OHM}$		5		ns
Rise Time	t_r			12		
Turn-Off Delay Time	$t_{d(off)}$			13		
Fall-Time	t_f			7		

SCHOTTKY SPECIFICATIONS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Conditions	Limits			Unit
			Min	Typ	Max	
Forward Voltage Drop	V_F	$I_F = 0.5 \text{ A}$			0.48	V
		$I_F = 0.5 \text{ A}, T_J = 125^\circ\text{C}$			0.4	V
Maximum Reverse Leakage Current	I_{rm}	$V_r = 30 \text{ V}$			0.1	mA
		$V_r = 30 \text{ V}, T_J = 75^\circ\text{C}$			1	
		$V_r = 30 \text{ V}, T_J = 125^\circ\text{C}$			10	
Junction Capacitance	C_T	$V_r = 10 \text{ V}$		31		pF

Notes

- a. Pulse test: PW <= 300us duty cycle <= 2%.
- b. Guaranteed by design, not subject to production testing.